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# Adiabatic Refractive Lenses for Making nm Sized Hard X-Ray Beams

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**Refractive X-Ray Optics** 

- first realized in 1996 (Snigirev et al.)
- a variety of refractive lenses have been developed since
- applied in full field imaging and scanning microscopy
- most important to achieve optimal performance:

aspherical lens shape





## **Effective Aperture and Diffraction Limit**



 $D_{\rm eff}$  limited by:

- geometric aperture 2R<sub>0</sub>
- attenuation inside lens material (includes Compton scattering)

 $\rightarrow$  low Z lens material

Numerical aperture:



$$NA = \sin \alpha = \frac{D_{\text{eff}}}{2L_2}$$

Diffraction limit:

$$d_t = 0.75 \cdot \frac{\lambda}{2NA}$$



## Numerical Aperture

large f. aperture dominated by attenuation

$$D_{\rm eff} = 4\sqrt{\frac{f\delta}{\mu}} \propto \sqrt{f}$$

- $\rightarrow$  reduce  $\mu/\delta$  (low Z lens material)
- $\rightarrow NA = D_{\rm eff}/2f \propto 1/\sqrt{f}$ : reduce focal size to minimum





Cornell, 24.06.2006



#### Nanofocusing Lenses (NFL)





#### **Crossed Nanofocusing Lenses**





### Focusing with NFLs

```
Si lens: E = 21 \text{keV}, L_1 = 47 \text{m}
```

source:

ID13 low- $\beta$  invac. undulator source size: 150 x 60 $\mu$ m<sup>2</sup>

vertical focus: 55nm



horizontal focus: 47nm





## Focusing with NFLs

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vertical focus: 55nm



horizontal focus: 47nm



roughness: ~ 10nm rms

APL 87, 124103 (2005)



## Effective Aperture and Diffraction Limit

Nanofocusing lens:

$$f_{\min} = \sqrt{f_0 L} = \sqrt{\frac{Rl}{2\delta}}$$
with  $f_0 = \frac{R}{2N\delta}$ 



10



Numerical Aperture of NFLs

$$NA = \frac{D_{\rm eff}}{2f_{\rm min}} \le \sqrt{2\delta}$$

Always smaller than critical angle of total reflection

Limits diffraction limit of NFLs to

$$d_t \ge 0.75 \cdot \frac{\lambda}{2\sqrt{2\delta}} > 10 \text{nm}$$

for useful lens materials



# Effective Aperture and Diffraction Limit Diffraction limit:



APL 82, 1485 (2003)



### Refractive Power per Unit Length



For large number of lenses:

$$r'' = \frac{d^2r}{dz^2} = -\omega^2 r$$

Beam oscillates inside of lens (analogy to harm. oscillator)





## Refractive Power per Unit Length



- increases with decreasing  $R_0$
- beam converges to focus inside of lens

aperture can be decreased without loss toward exit of lens

increase  $\omega^2$  toward exit of lens





adjust  $R_0$  to fit the converging beam as it is focused:

$$\omega^2 = \frac{2\delta}{l_j R_j} \approx \frac{2\delta}{R_{0j}^2}$$

Solve

$$r'' = -\omega(z)r$$

for peripheral ray *R*<sub>0</sub>(*z*) PRL 94, 054802 (2005) Cornell, 24.06.2006





$$R_0'' = -\frac{2\delta}{R_0}$$

First integral:

$$\frac{1}{2}(R_0')^2 + 2\delta \log(R_0) = E$$

*E* defined by initial conditions For example:

 $R_0' = 0, R_0 = R_{0i}$ 

PRL 94, 054802 (2005) Cornell, 24.06.2006





First order differential eq.:

$$R_0' = \sqrt{4\delta \log \frac{R_{0i}}{R_0}}$$

Solution shown to the right







Numerical aperture:

(char. aperture)

$$NA = \sqrt{\delta} \sqrt{4 \frac{a}{R_{0i}} \left[1 - \exp\left(-\frac{R_{0i}}{a}\right)\right] \log \frac{R_{0i}}{R_{0f}}}, \text{ with } a = \frac{2\sqrt{\delta}}{\sqrt{\pi}\mu}$$

 $\delta$  large: high density  $\rho$ *a* large: low absorption (low Z)  $\rightarrow$  material parameters

 $\rightarrow$  optimal material: diamond (high density, low Z)

 $\begin{array}{c} R_{0i} \text{ set to maximize } NA (0.6 - 1 \cdot a) \\ R_{0f} \text{ set to minimal value} \end{array} \right\} \text{ fabrication parameters} \\ \begin{array}{c} PRL 94, 054802 (2005) \\ Cornell, 24.06.2006 \end{array}$ 



## Example AFL

#### Diamond lens:

low atomic number Z and high density  $\rho$ 

N = 1166 individual lenses entrance aperture: 18.9µm exit aperture: 100nm f = 2.3mm

diffraction limit: 14.2nm

diffraction limit: 4.7nm

compare to NFL:

same aperture

#### (a) contracting wave field inside lens





## Example AFL

#### **Diamond lens:**

low atomic number Z and high density  $\rho$ 

N = 1166 individual lenses entrance aperture: 18.9µm exit aperture: 100nm *f*=2.3mm

(a) contracting wave field inside lens



diffraction limit: 4.7nm

Flux in focus (@20 keV, same focus size

ERL hi-coh (15pm, 10mA): ~ 10<sup>11</sup> ph/s ERL hi-coh (8pm, 25mA): ~ 10<sup>12</sup> ph/s ESRF, Invac. undulator: ~  $10^9$  ph/s  $\rightarrow 10^7 - 10^8$  ph/Å<sup>2</sup>/s!! Cornell, 24.06.2006

 $DOF = 1.1 \mu m$ 



## Example AFL

kinoform lens: segment size follows converging beam



No sharp fundamental limit! Practical implementation difficult! but

No atomic resolution in direct imaging with refractive lenses!

PRL 94, 054802 (2005) 21



Refractive Lenses: Summary

Numerical aperture limited:

- limited density of low Z materials limits  $\delta$
- characteristic aperture *a* limits initial aperture  $R_{0i}$  (as result of attenuation)
- fabrication and atomic structure limits exit aperture  $R_{0f}$



Wave Propagation Through FZP parabolic wave equation:

$$2ik\frac{\partial u}{\partial z} + \frac{\partial^2 u}{\partial x^2} + \frac{\partial^2 u}{\partial y^2} + k^2 \left(n^2(x, y, z) - 1\right)u = 0$$

 $n(x, y, z) = 1 - \delta(x, y, z) + i\beta(x, y, z)$  complex potential!

Ni/vac. zone plate  $E = 20 \text{ keV}, r_M(0) = 0.8 \mu \text{m}$  $\Delta r_M = 1 \text{nm}$ 

(inspired by poster by F. Pfeiffer at XRM2005) Cornell, 24.06.2006





Wave Field Inside FZP



ideal tilted FZP [Kang, et al., PRL 96 127401 (2006)]

incoming plane wave

propagate exit wave field to focus









## FZP: Summary

no limit as long as matter is homogeneous

multilayers have been shown to behave homogeneously down to below 2 nm *d*-spacing (1 nm layers)

high efficiency, since only one diffraction order is excited!

atomicity will limit zone placement!

other optics may be calculated similarly!

PRB, **74** (July 15, 2006) Cornell, 24.06.2006





#### Wave Front in Diffraction Limited Focus



$$d_t = \frac{2\sqrt{2\ln 2}}{\pi} \frac{\lambda}{2NA} \approx 0.75 \frac{\lambda}{2NA}$$

Gaussian limited plane wave





## Wave Front in Diffraction Limited Focus

Lateral coherence length in nanofocused beam:



Coherent diffraction at nanoparticles possible, as long as particles are smaller than diffraction limit.



Coherence in the Focus Si NFL @ ID13, *E* = 15keV nominal parameters: FWHM focus size: 66 x 75 nm<sup>2</sup> diff. limit: 54 x 71 nm<sup>2</sup> lateral coherence length: 120 x 300 nm<sup>2</sup> divergence (*NA*): 0 58 x 0 43 mrad<sup>2</sup> Cornell, 24.06.2006

Preliminary experiment: **Diffraction from Fe-particles** ( $\sim$  40nm diam., on Si<sub>3</sub>N<sub>4</sub> membrane, from R. Röhlsberger)



(exposure: 10 s) Visibility reduced: mechanical instability! horiz. beam size: 120nm



## Scanning Coherent Diffraction Microscopy

bridge the "small" gap to atomic resolution by using coherent diffraction imaging contrast





## Scanning Coherent Diffraction Microscopy

bridge the "small" gap to atomic resolution by using coherent diffraction imaging contrast



smaller q-range (WAXS)

reduced requirements on dynamic range of detector

larger detector pixels

short local exposure (up to 10<sup>7</sup>ph/Å<sup>2</sup>)



## Conclusion

**Refractive optics:** 

- hard x-ray beams of 5nm seem feasible (limiting factor is attenuation and atomicity of matter)
- kinoform lenses would reduce focus size (feasibility?)

Fresnel zone plates (tilted):

 focus below 1 nm should be feasible (limiting factor is atomicity of matter)

Challenging experiment:

scanning coherent diffraction microscopy



AFLs Made of Silicon

entrance aperture:  $2R_{0i} = 20\mu m$ exit aperture:  $2R_{0f} = 1\mu m$ energy: 10 - 20keV in 500eV steps



properties:

f = 2.7mm  $d_{\rm t} = 12.6$ nm

as horizontal lens in x-ray nanoprobe (e. g. ID13 ESRF):

 $L_1 = 47$ m, source size: 150µm

horizontal focus: 15.3nm (17400 x reduction)



## Far Field of Focus: Aberrations Si NFL @ ID13, *E* = 15keV Far field image of focus:



detector dist.: 800mm log (I) Cornell, 24.06.2006 Structure:

irregularities in lens shape

reconstruction of lens shape? [Quiney, et al., Nat. Phys. 2, 101 (2006)]



**Optimal Numerical Aperture of Single Lens** 

First scenario:



Works as long as ray is not totally reflected

Deflection angle <  $\sqrt{2\delta}$ 

NA limited by  $\sqrt{2\delta}$ even for non-absorbing material



**Optimal Numerical Aperture of Single Lens** 

Second scenario:

